

<b>Notice of References Cited</b>	Application/Control No. 10/723,419	Applicant(s)/Patent Under Reexamination EISENSCHMID ET AL.	
	Examiner Stanley J. Pruchnic, Jr.	Art Unit 2859	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,257,775 A	03-1981	Ladov et al.	436/40
	B	US-6,308,564 B1	10-2001	Wehrmeyer et al.	73/304R
	C	US-6,787,047 B1	09-2004	Hahn et al.	216/2
	D	US-2005/0013340 A1	01-2005	Frost, Derek E.	374/016
	E	US-6,869,273 B2	03-2005	Crivelli, Paul	417/53
	F	US-6,407,479 B1	06-2002	Moellendorf et al.	310/313A
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Micro-sensor with integrated resistance thermometer element," English language abstract of DE 19710358 (September 1998); Flik et al.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.